# Half Bridge Gate Driver (Isolated High & Non-Isolated Low)

# NCD57200

The NCD57200 is a high voltage gate driver with one non-isolated low side gate driver and one galvanically isolated high or low side gate driver. It can directly drive two IGBTs in a half bridge configuration. Isolated high side driver can be powered with an isolated power supply or with Bootstrap technique from the low side power supply.

The galvanic isolation for the high side gate driver guarantees reliable switching in high power applications for IGBTs that operate up to 800 V, at high dv/dt. The optimized output stages provide a mean of reducing IGBT losses. Its features include two independent inputs with deadtime and interlock, accurate asymmetric UVLOs, and short and matched propagation delays. The NCD57200 operates with its  $V_{DD}/V_{BS}$  up to 20 V.

#### **Features**

- High Peak Output Current (+1.9 A/-2.3 A)
- Low Output Voltage Drop for Enhanced IGBT Conduction
- Floating Channel for Bootstrap Operation up to +800 V
- CMTI up to 100 kV/µs
- Reliable Operation for V<sub>S</sub> Negative Swing to -800 V
- VDD & VBS Supply Range up to 20 V
- 3.3 V, 5 V, and 15 V Logic Input
- Asymmetric Under Voltage Lockout Thresholds for High Side and Low Side
- Matched Propagation Delay 90 ns
- Built-in 20 ns Minimum Pulse Width Filter (or Input Noise Filter)
- Built-in 340 ns Dead-Time and High and Low Inputs Interlock
- Non-Inverting Output Signal
- This Device is Pb–Free, Halogen Free/BFR Free and is RoHS Compliant

#### **Typical Applications**

- Fans, Pumps
- Home Appliances
- Consumer Electronics
- General Purpose Half Bridge Applications



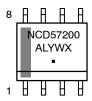
# ON Semiconductor®

www.onsemi.com



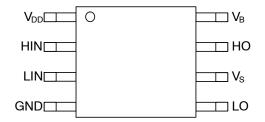
SOIC-8 NB CASE 751-07

#### **MARKING DIAGRAM**



NCD57200 = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
= Pb-Free Package

#### **PIN CONNECTIONS**



# ORDERING INFORMATION

See detailed ordering and shipping information on page 15 of this data sheet.

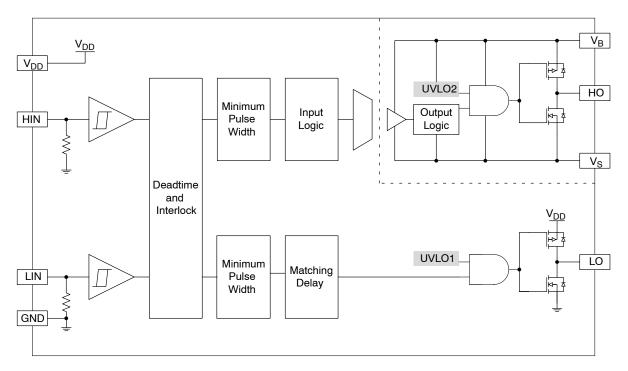


Figure 1. Simplified Block Diagram

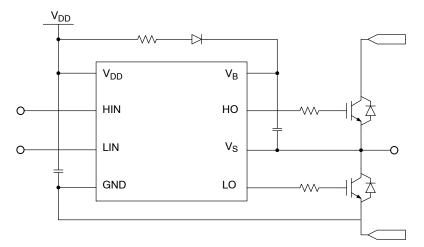


Figure 2. Simplified Application Schematics

**Table 1. FUNCTION DESCRIPTION** 

Pin Name	No.	I/O	Description
$V_{DD}$	1	Power	Low side and main power supply. A good quality bypassing capacitor is required from this pin to GND and should be placed close to the pins for best results.  The under voltage lockout (UVLO) circuit enables the device to operate at power
			on when a typical supply voltage higher than $V_{UVLO1-OUT-ON}$ is present. Please see Figure 5 for more details. A filter time $t_{UVF1}$ helps to suppress noise on $V_{DD}$ pin.
HIN	2	I	High side non-inverting gate driver input. It has an equivalent pull–down resistor of 125 k $\Omega$ to ensure that output is low in the absence of an input signal. A minimum positive or negative going pulse width is required at HIN before HO reacts.
			It adopts 3.3 V logic signal thresholds for input voltage up to $V_{DD}$ . There is deadtime and interlocking logic between HIN and LIN.
LIN	3	ı	Low side non-inverting gate driver input. It has an equivalent pull-down resistor of 125 k $\Omega$ to ensure that output is low in the absence of an input signal. A minimum positive or negative going pulse width is required at LIN before LO reacts.
			It adopts 3.3 V logic signal thresholds for input voltage up to $V_{DD}$ . There is deadtime and interlocking logic between HIN and LIN.
GND	4	Power	Logic ground and low side driver return.
LO	5	0	Low side driver output that provides the appropriate drive voltage and source/ sink current to the IGBT gate. LO is actively pulled low during startup and under UVLO1 condition. There is deadtime and interlocking logic to prevent unintended HO and LO cross conduction.
V <sub>S</sub>	6	Power	Bootstrap return or high side floating supply offset.
НО	7	0	Galvanically isolated high side driver output that provides the appropriate drive voltage and source/sink current to the IGBT gate. HO is actively pulled low during startup and under UVLOx condition. There is deadtime and interlocking logic to prevent unintended HO and LO cross conduction.
V <sub>B</sub>	8	Power	Bootstrap or high side floating power supply. A good quality bypassing capacitor is required from this pin to $V_S$ and should be placed close to the pins for best results.
			The under voltage lockout (UVLO) circuit enables the device to operate at power on when a typical supply voltage higher than V <sub>UVLO2-OUT-ON</sub> is present. Please see Figure 5 for more details. A filter time t <sub>UVF2</sub> helps to suppress noise on V <sub>B</sub> pin.

Table 2. ABSOLUTE MAXIMUM RATINGS (Note 1) Over operating free-air temperature range unless otherwise noted

Parameter	Symbol	Minimum	Maximum	Unit
High-Side Offset Voltage (see Figure 2)	V <sub>S</sub>	-900	900	V
High-Side Supply Voltage (see Figure 2)	V <sub>B</sub>	-900	900	V
Low-Side Supply Voltage	$V_{DD}$	-0.3	25	٧
High-Side Floating Supply Voltage	V <sub>BS</sub>	-0.3	25	٧
High-Side Output Voltage (HO) (see Figure 2)	V <sub>HO</sub>	V <sub>S</sub> -0.3	V <sub>BS</sub> +0.3	V
Low-Side Output Voltage (LO)	$V_{LO}$	-0.3	V <sub>DD</sub> +0.3	V
Logic Input Voltage (HIN, LIN)	V <sub>IN</sub>	-0.3	V <sub>DD</sub> +0.3	V
Allowable Offset Voltage Slew Rate (see Figure 32)	dV <sub>S</sub> /dt		±100	V/ns
Maximum Junction Temperature	TJ(max)	-40	150	°C
Storage Temperature Range	TSTG	-65	150	°C
ESD Capability, Human Body Model (Note 2)	ESDHBM		±4	kV
ESD Capability, Charged Device Model (Note 2)	ESDCDM		±2	kV
Moisture Sensitivity Level	MSL		1	-
Lead Temperature Soldering Reflow	TSLD		260	°C
(SMD Styles Only), Pb-Free Versions (Note 3)				

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.
- 2. This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per AEC-Q100-002 (EIA/JESD22-A114).
  - ESD Charged Device Model tested per AEC-Q100-002 (EIA/JESD22-A114).
  - Latchup Current Maximum Rating: ≤ 100 mA per JEDEC standard: JESD78, 125°C.
- 3. For information, please refer to our Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

### **Table 3. THERMAL CHARACTERISTICS**

Parameter	Symbol	Value	Unit
Thermal Characteristics, SOIC-8 (Note 4) Thermal Resistance, Junction-to-Air (Note 5)	Reja	167	°C/W

- 4. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.
- 5. Values based on copper area of 100 mm2 (or 0.16 in2) of 1 oz copper thickness and FR4 PCB substrate.

### Table 4. RECOMMENDED OPERATING RANGES (Note 6)

Parameter	Symbol	Min	Max	Unit
High-Side Floating Supply Voltage	V <sub>BS</sub>	V <sub>S</sub> +UVLO2	V <sub>S</sub> +20	V
High-Side Offset Voltage (see Figure 2)	Vs	-800	800	V
High-Side Output Voltage (HO) (see Figure 2)	V <sub>HO</sub>	Vs	V <sub>BS</sub>	V
Low-Side Output Voltage (LO)	$V_{LO}$	GND	$V_{DD}$	V
Logic Input Voltage (HIN, LIN)	V <sub>IN</sub>	GND	$V_{DD}$	V
Low-Side Supply Voltage	V <sub>DD</sub>	UVLO1	20	V
Ambient Temperature	T <sub>A</sub>	-40	+125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

6. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

 $\begin{tabular}{ll} \textbf{Table 5. ELECTRICAL CHARACTERISTICS}$ $V_{DD} = V_{BS} = 15$ V. \\ For typical values $T_A = 25^{\circ}$C, for min/max values, $T_A$ is the operating ambient temperature range that applies, unless otherwise noted. \\ \end{tabular}$ 

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
VOLTAGE SUPPLY						
V <sub>BS</sub> Supply Under Voltage Output Enabled		V <sub>UVLO2</sub> OUT	11	11.5	12	V
V <sub>BS</sub> Supply Under Voltage Output Disabled		V <sub>UVLO2</sub> OUT OFF	10	10.5	11	V
V <sub>BS</sub> Supply Voltage Output Enabled/Disabled Hysteresis		V <sub>UVLO2-HYST</sub>	0.5	1.0	1.2	V
V <sub>DD</sub> Supply Under Voltage Output Enabled		V <sub>UVLO1</sub> -OUT -ON	12	12.5	13	V
V <sub>DD</sub> Supply Under Voltage Output Disabled		V <sub>UVLO1</sub> OUT	11	11.5	12	V
V <sub>DD</sub> Supply Voltage Output Enabled/Disabled Hysteresis		V <sub>UVLO1-HYST</sub>	0.5	1.0	1.2	V
Leakage Current Between $V_S$ and GND	$V_S = \pm 800 \text{ V}, T_A = 25^{\circ}\text{C}$ $V_S = \pm 800 \text{ V}, T_A = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	I <sub>HV_LEAK1</sub> I <sub>HV_LEAK2</sub>		20	200 600	nA
Quiescent Current V <sub>BS</sub> Supply (V <sub>B</sub> Only)	HO = Low	I <sub>QBS1</sub>		260	325	μΑ
Quiescent Current V <sub>BS</sub> Supply (V <sub>B</sub> Only)	HO = High	I <sub>QBS2</sub>		330	440	μΑ
Quiescent Current $V_{\rm DD}$ Supply (V <sub>DD</sub> Only)	V <sub>LIN</sub> = Float, V <sub>HIN</sub> = 0 V,	I <sub>QDD1</sub>		380	440	μΑ
Quiescent Current $V_{\mathrm{DD}}$ Supply (V <sub>DD</sub> Only)	V <sub>LIN</sub> = 3.3 V, V <sub>HIN</sub> = 0 V,	I <sub>QDD2</sub>		440	500	μΑ
Quiescent Current $V_{\rm DD}$ Supply (V <sub>DD</sub> Only)	V <sub>LIN</sub> = 0 V, V <sub>HIN</sub> = 3.3 V,	I <sub>QDD3</sub>		2.4	3	mA
LOGIC INPUT		•			•	
Low Level Input Voltage		V <sub>IL</sub>			0.9	V
High Level Input Voltage		V <sub>IH</sub>	2.4			V
Logic "1" Input Bias Current	V <sub>LIN</sub> = 3.3 V, V <sub>HIN</sub> = 3.3 V	I <sub>LIN1+</sub> , I <sub>HIN1+</sub>		25	50	μΑ
Logic "1" Input Bias Current	V <sub>LIN</sub> = 20 V, V <sub>HIN</sub> = 20 V, V <sub>DD</sub> = V <sub>BS</sub> = 20 V	I <sub>LIN2+</sub> , I <sub>HIN2+</sub>		100	150	μΑ
Logic "0" Input Bias Current	V <sub>LIN</sub> = 0 V, V <sub>HIN</sub> = 0 V	I <sub>LIN</sub> -, I <sub>HIN</sub> -		40	100	nA
DRIVER OUTPUT						
Output Low State	I <sub>SINK</sub> = 200 mA, T <sub>A</sub> = 25°C	V <sub>OL1</sub>		0.2	0.3	V
	$I_{SINK} = 200 \text{ mA},$ $T_{A} = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	V <sub>OL2</sub>			0.5	
Output High State	I <sub>SOURCE</sub> = 200 mA, T <sub>A</sub> = 25°C	V <sub>OH1</sub>	14.4	14.5		V
	I <sub>SOURCE</sub> = 200 mA, T <sub>A</sub> = -40°C to 125°C	V <sub>OH2</sub>	14			
Peak Driver Current, Sink	V <sub>HO</sub> = V <sub>LO</sub> = 15 V	I <sub>PK-SNK1</sub>		2.3		Α
(Note 7)	V <sub>HO</sub> = V <sub>LO</sub> = 9 V (near Miller Plateau)	I <sub>PK-SNK2</sub>		2.1		
Peak Driver Current, Source	V <sub>HO</sub> = V <sub>LO</sub> = 0 V	I <sub>PK-SRC1</sub>		1.9		Α
(Note 7)	V <sub>HO</sub> = V <sub>LO</sub> = 9 V (near Miller Plateau)	I <sub>PK-SRC2</sub>		1.5		

Table 5. ELECTRICAL CHARACTERISTICS  $V_{DD}$  =  $V_{BS}$  = 15 V.

For typical values  $T_A = 25^{\circ}C$ , for min/max values,  $T_A$  is the operating ambient temperature range that applies, unless otherwise noted.

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
IGBT SHORT CIRCUIT CLAMPING						
Clamping Voltage (V <sub>HO</sub> - V <sub>B</sub> ) / (V <sub>LO</sub> - V <sub>DD</sub> )	$I_{HO}$ = 100 mA, $I_{LO}$ = 100 mA (pulse test, $t_{CLPmax}$ = 10 μs)	V <sub>CLAMP-OUT</sub>		0.8	1.3	V
DYNAMIC CHARACTERISTIC						
HO High Propagation Delay	C <sub>LOAD</sub> = 1 nF, V <sub>IH</sub> to 10% of Output Change for PW > 150 ns	<sup>t</sup> PD-ON-H	50	90	110	ns
HO Low Propagation Delay	C <sub>LOAD</sub> = 1 nF, V <sub>IL</sub> to 90% of Output Change for PW > 150 ns	t <sub>PD-OFF-H</sub>	50	90	110	ns
Propagation Delay Distortion(HS) (= t <sub>PD-ON-H</sub> - t <sub>PD-OFF-H</sub> )	PW >150 ns	t <sub>DISTORT-H</sub>	-25	0	25	ns
LO High Propagation Delay	C <sub>LOAD</sub> = 1 nF, V <sub>IH</sub> to 10% of Output Change for PW > 150 ns	t <sub>PD-ON-L</sub>	50	90	110	ns
LO Low Propagation Delay	C <sub>LOAD</sub> = 1 nF, V <sub>IL</sub> to 90% of Output Change for PW > 150 ns	t <sub>PD-OFF-L</sub>	50	90	110	ns
Propagation Delay Distortion(LS) (= t <sub>PD-ON-L</sub> - t <sub>PD-OFF-L</sub> )	PW >150 ns	t <sub>DISTORT-L</sub>	-25	0	25	ns
High Propagation Delay Distortion between High and Low Sides	PW > 150 ns	t <sub>DISTORT-HL-H</sub>	-25	0	25	ns
Low Propagation Delay Distortion between High and Low Sides	PW > 150 ns	t <sub>DISTORT-HL-L</sub>	-25	0	25	ns
Rise Time (HO) (see Figure 3)	C <sub>LOAD</sub> = 1 nF, 10% to 90% of Output Change	t <sub>RISE-H</sub>		13		ns
Fall Time (HO) (see Figure 3)	C <sub>LOAD</sub> = 1 nF, 90% to 10% of Output Change	t <sub>FALL-H</sub>		8		ns
Rise Time (LO) (see Figure 3)	C <sub>LOAD</sub> = 1 nF, 10% to 90% of Output Change	t <sub>RISE-L</sub>		13		ns
Fall Time (LO) (see Figure 3)	C <sub>LOAD</sub> = 1 nF, 90% to 10% of Output Change	t <sub>FALL-L</sub>		8		ns
Deadtime, HO Delays (see Figure 6)	V <sub>LIN/HIN</sub> = 0 V and 3.3 V	t <sub>DT1</sub>		340		ns
Deadtime, LO Delays (see Figure 6)	V <sub>LIN/HIN</sub> = 0 V and 3.3 V	t <sub>DT2</sub>		350		ns
Deadtime Matching		t <sub>MDT</sub>		10		ns
Minimum Pulse Width Filtering Time (see Figure 3)	T <sub>A</sub> = 25°C	t <sub>MIN1</sub> , t <sub>MIN2</sub>	10		40	ns
UVLO Fall Delay (HO and LO)		t <sub>UVF1</sub> , t <sub>UVF2</sub>		1300		ns
UVLO Rise Delay (HO and LO)		t <sub>UVR1</sub> , t <sub>UVR2</sub>		1100		ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

7. Values based on design and/or characterization.

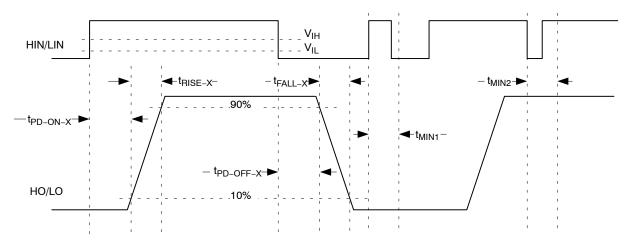


Figure 3. Propagation Delay, Rise and Fall Time

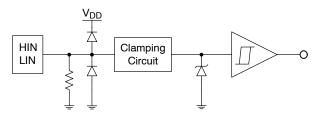


Figure 4. Input Pin Structure

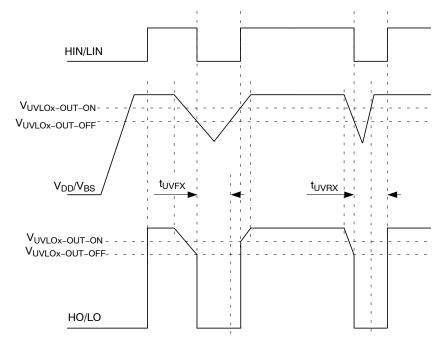


Figure 5. UVLO

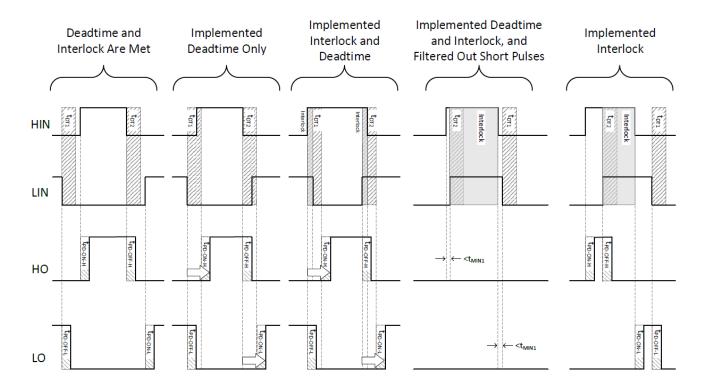


Figure 6. Deadtime, Interlock and Output Minimum Pulse Width

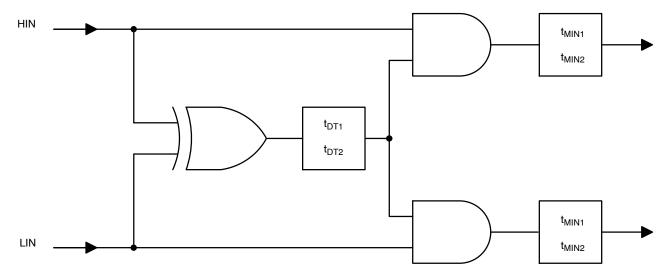
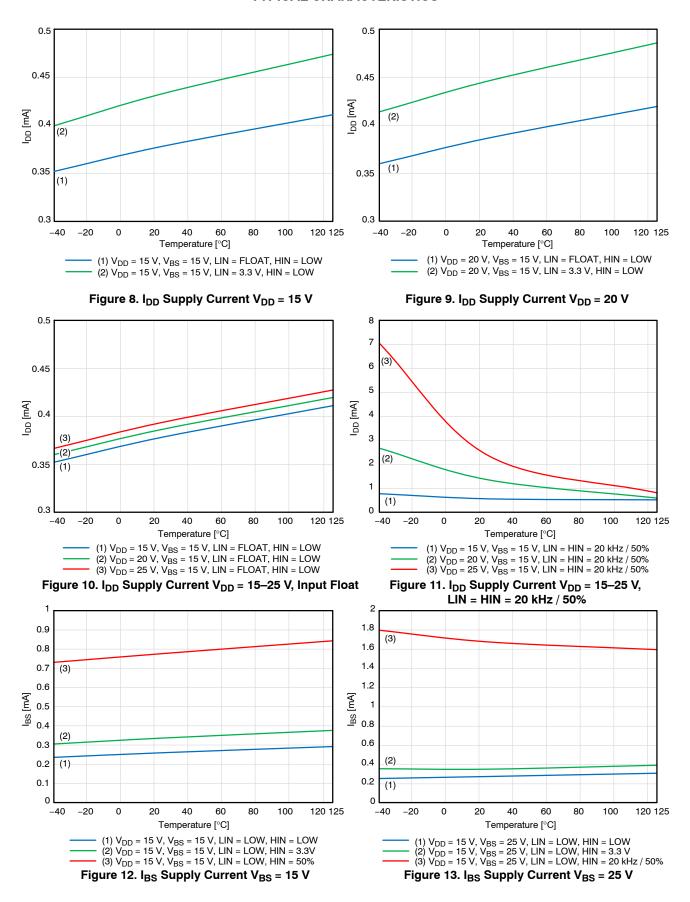
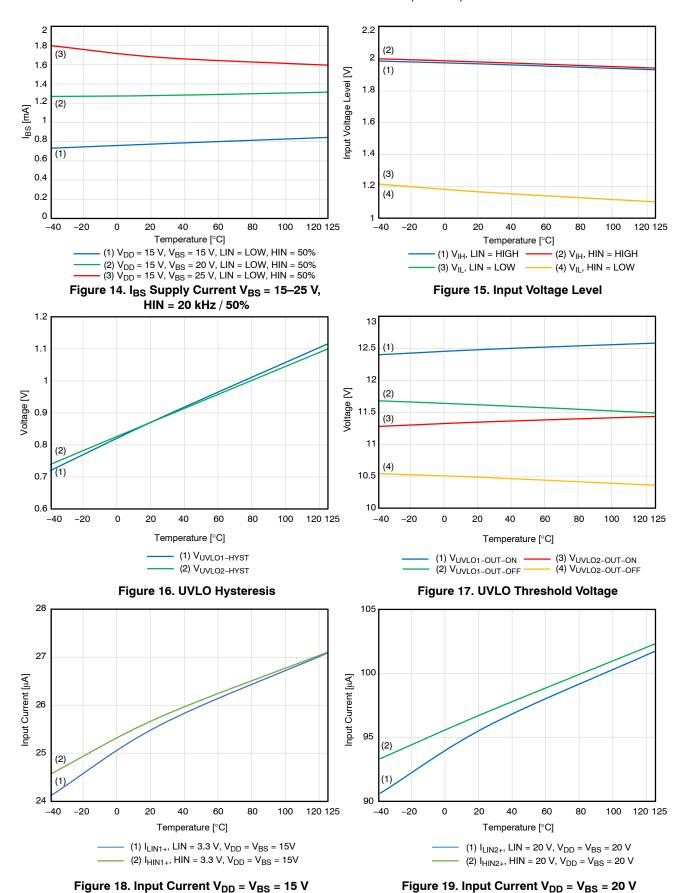


Figure 7. Input Circuit

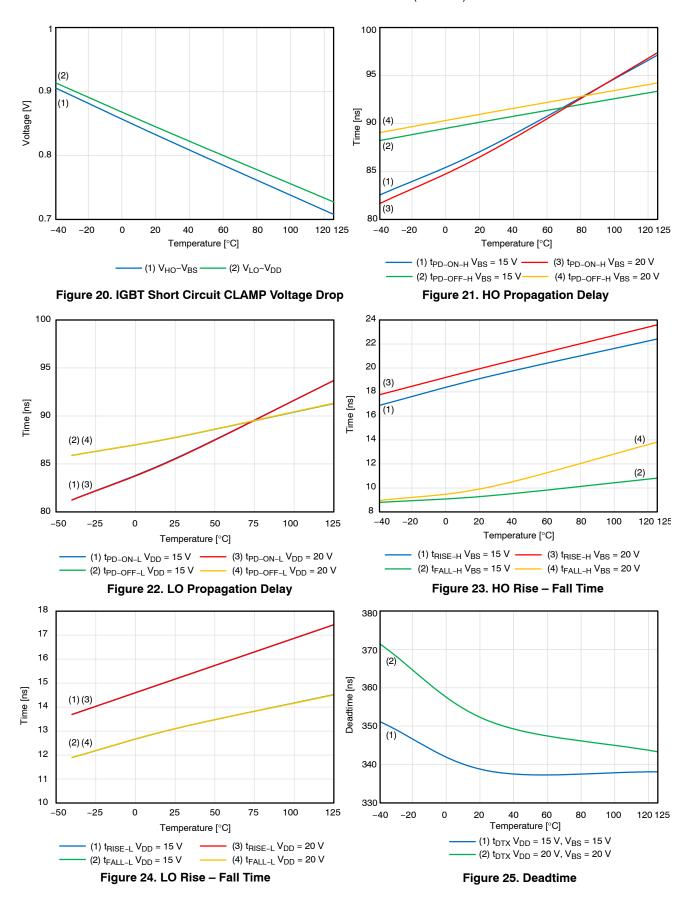
#### TYPICAL CHARACTERISTICS



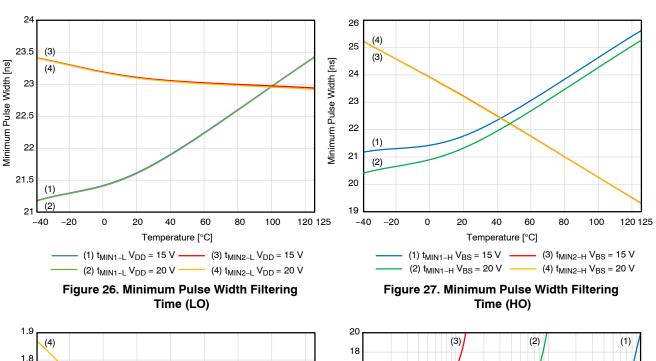
# TYPICAL CHARACTERISTICS (continued)



### TYPICAL CHARACTERISTICS (continued)



### TYPICAL CHARACTERISTICS (continued)



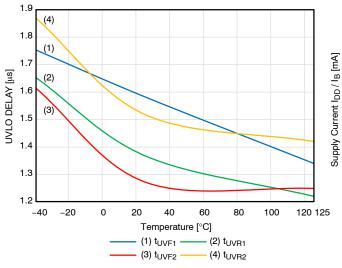


Figure 28. UVLO Delay

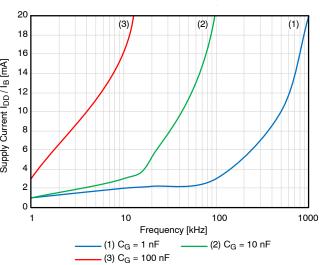


Figure 29. Power Supply Current vs. Switching Frequency (Duty Cycle 50%)

#### **Under Voltage Lockout (UVLO)**

UVLO ensures correct switching of IGBT connected to the driver output.

- ullet The IGBT is turned-off, if the supply  $V_{DD}$  drops below V<sub>UVLO1-OUT-OFF</sub> or V<sub>BS</sub> drops below V<sub>UVLO2-OUT-OFF</sub>
- The driver output does not start to react to the input signal on HIN or LIN until the V<sub>DD</sub> or V<sub>BS</sub> rises above the  $V_{UVLOX-OUT-ON}$

# Power Supply (V<sub>DD</sub>, V<sub>BS</sub>)

NCD57200 is designed to support unipolar power supply on both individual channels.

For reliable high output current suitable external power capacitors are required. Parallel combination of 100 nF + 4.7 μF ceramic capacitors is optimal for a wide range of applications using IGBT. For reliable driving of IGBT modules (containing several parallel IGBTs) a higher capacitance is required (typically 100 nF + 10 μF). Capacitors should be as close as possible to the driver's power pins.

Power supply of isolated (HO) channel can be provided by an external DC power supply or Bootstrap circuit.

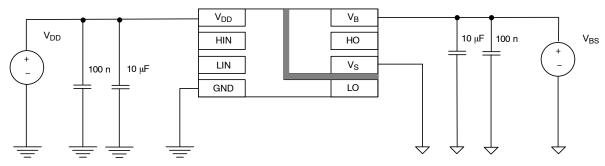


Figure 30. Unipolar Power Supply

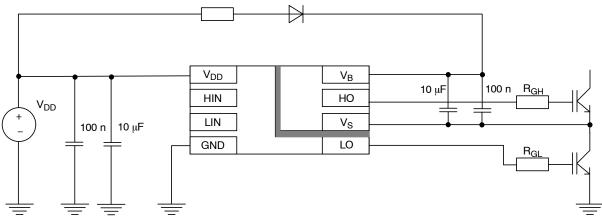


Figure 31. Bootstrap Power Supply

#### Signal Inputs (HIN, LIN)

Inputs of NCD57200 are active high. Outputs are in phase with inputs signals respecting internal logic (see Figure 5, 6, 7).

**WARNING:** When the application uses an independent or separate power supply for the control unit on the input side of the driver, all inputs should be protected by a serial resistor (In case of a power failure of the driver, the driver may be damaged due to overloading of the input protection circuits).

# **Common Mode Transient Immunity (CMTI)**

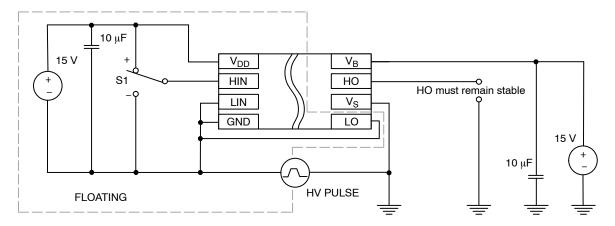


Figure 32. CMTI Test Setup

(Test Conditions: HV PULSE =  $\pm 900$  V, dV/dt = 1-100 V/ns,  $V_{DD} = 15$  V,  $V_{B} = 15$  V)

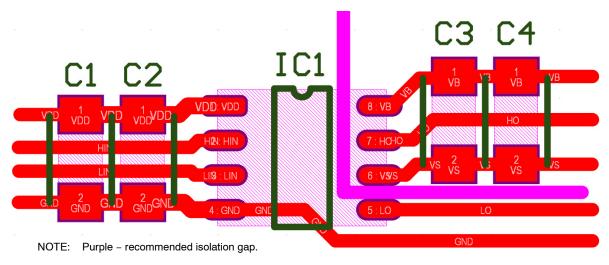


Figure 33. Recommended Layout

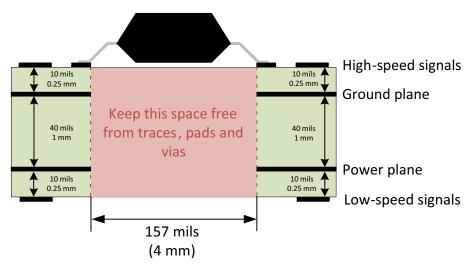


Figure 34. Recommended Layer Stack

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NCD57200DR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

#### **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

#### **STYLES ON PAGE 2**

DOCUMENT NUMBER:	98ASB42564B	Electronic versions are uncontrolled except when accessed directly from the Document Repos Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2	

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

# SOIC-8 NB CASE 751-07 ISSUE AK

# DATE 16 FEB 2011

STYLE 3: PIN 1. DRAIN, PIE #1 CTOR, #1 CTOR, #2 CTOR, #1 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #1	2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE  STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #1 Vd  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #1
E PIN 1. INPUT 2. EXTERNAL BY 3. THIRD STAGE 4. GROUND E 5. DRAIN 6. GATE 3 7. SECOND STAGE 8. FIRST STAGE STYLE 11: ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 ID	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 Vd 8. COLLECTOR, #1  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 STYLE 15: RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
STYLE 15:  RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
N 7. CATHODE, CON N 8. CATHODE, CON	MMON         5. COLLECTOR, DIE #2           MMON         6. COLLECTOR, DIE #2           MMON         7. COLLECTOR, DIE #1           MMON         8. COLLECTOR, DIE #1
STYLE 19: PIN 1. SOURCE 1 E 2. GATE 1 E 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 DE 7. DRAIN 1 DE 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 23: E1 PIN 1. LINE 1 IN DN CATHODE/VCC 2. COMMON ANC DN CATHODE/VCC 3. COMMON ANC E3 4. LINE 2 IN DN ANODE/GND 5. LINE 2 OUT E4 6. COMMON ANC E5 7. COMMON ANC DN ANODE/GND 8. LINE 1 OUT	ODE/GND 2. EMITTER ODE/GND 3. COLLECTOR/ANODE
STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V MON 6. VBULK 7. VBULK 8. VIN
1 1	
;	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ E 5. SOURCE E 6. SOURCE E 7. SOURCE 8. DRAIN

DOCUMENT NUMBER:	98ASB42564B Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	SOIC-8 NB		PAGE 2 OF 2	

ON Semiconductor and IN are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

**TECHNICAL SUPPORT** North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada

Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative